




Research Article

Hydrothermally development of boron-integrated graphene nanoparticles for p-n junction diode applications

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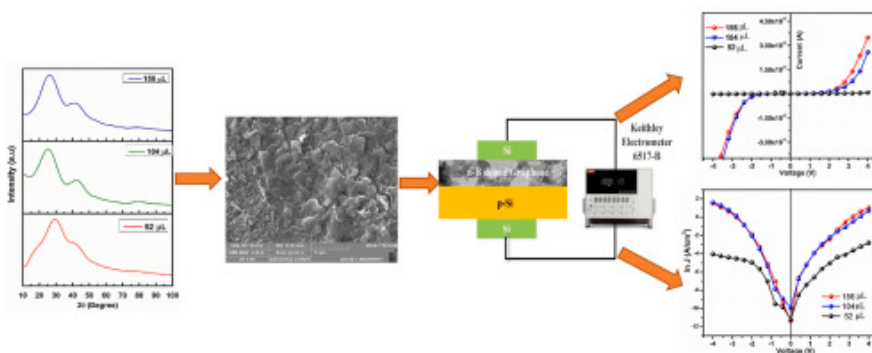
Highlights

- Boron doped graphene nanoparticles were synthesized by the hydrothermal route for various concentrations of Boron tribromide.
- XRD pattern exhibited a hexagonal crystal structure with sharp crystalline peak at (002) orientation.
- A sheet-like surface morphology was observed through SEM image.
- TEM images confirm the particle size was reduced upon increasing boron tribromide.
- A minimum ideality factor of $n=2.9$ was obtained for p-Si/n-B-doped Graphene diode fabricated with 156 μ L.

Abstract

In this work, boron doped graphene nanoparticles (NPs) were synthesized by the hydrothermal route with different boron tribromide concentrations such as 52, 104, and 156 μL . The structural, morphological and optical properties of the prepared NPs were studied using different characterization techniques such as X-ray diffraction (XRD), scanning electron microscope (SEM), transmission electron microscope (TEM), atomic force microscopy (AFM), UV-vis spectroscopy and photoluminescence spectroscopy (PL). The XRD pattern reveals the hexagonal crystal structure. The SEM image showed textured sheet-like layers which got agglomerated to form fluffy structures. The TEM images recorded single-crystalline nature and also confirms the particle size was reduced upon increasing boron tribromide solution concentration with recognizable particle shape. The topographic properties of the synthesized B-doped graphene NPs were also studied through AFM images. The UV visible absorbance characteristics peaks 243 and 372 nm were observed correspond to $\pi - \pi^*$ in C-C bands and n- π^* transition. After that as grown NPs were used to fabricate diode junctions on p-Si substrates (p-Si/n-B-doped graphene). The electrical performance of each p-Si/n-B-doped graphene diodes junction was examined using I-V characteristics and electrical parameters of diode junction such as ideality factor, barrier height and reverse saturation current were found 2.9–4.3, 0.75–0.83 eV and 4.88×10^{-6} – 7.26×10^{-6} A. The calculated ideality factor values of the p-Si/n-B-doped graphene diodes are decreased with increase in boron tribromide solution concentration.

Graphical abstract



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Introduction

Two-dimensional materials are highly attractive optoelectronic industry due to their exceptional physicochemical properties [[1], [2], [3]]. Graphene materials with extremely low-dimensional crystallinity and semiconducting nature are great advantageous for developing optoelectronic, catalytic energy generation, and energy storage applications [[4], [5], [6]]. Graphene facilitates the doping of various metal or nonmetal ions in the sites and functionalization of carbon which interestingly tunes their physicochemical and electronic properties. Graphene-based nanostructures such as doping, co-doping, and graphene decorative composites were receiving high attention among optoelectronic and environmental researchers to overcome the toxicity [7,8]. Various doping techniques were followed to achieve highly precise material for targeted applications [[9], [10], [11]]. Non-metal hetero-atoms are usually preferred for doping graphene-based materials to retain the